

**Search Notes**

Application/Control No.

10/725,379

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

TOBITA ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	65,68,70 72	4/1/2006	SWH
29	updated	4/1/2006	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPGPUB text search (see attached)	4/1/2006	SWH